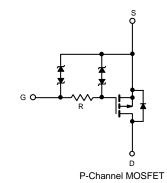


SOT-23

P-Channel 25-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
- 25	0.028 at $V_{GS} = -10 \text{ V}$	- 8 ^a	19 nC		
	0.036 at V _{GS} = - 4.5 V	- 6 ^a	19110		



FEATURES

- **DT-Trench Power MOSFET**
- 100 % R_g Tested Built in ESD Protection with Zener Diode
- Typical ESD Performance: 1800 V
- Compliant to RoHS Directive 2002/95/EC



APPLICATIONS

- Portable Devices
 - Load Switch
 - Battery Switch
 - Charger Switch

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 25	V	
Gate-Source Voltage		V _{GS}	± 12		
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$	I _D	- 8 ^a - 6 ^a - 6 ^{b, c}		
Pulsed Drain Current	T _A = 70 °C	I _{DM}	- 4.7 ^{b, c} - 26	A	
Continuous Source-Drain Diode Current	$\frac{T_C = 25 \text{ °C}}{T_A = 25 \text{ °C}}$	I _S	- 7 ^a - 3.5 ^{b, c}		
Maximum Power Dissipation	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	P _D	18 11 3.3 ^{b, c} 2.1 ^{b, c}	w	
Operating Junction and Storage Temperature Rai	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature	, and the second	260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, e}	t ≤ 5 s	R _{thJA}	28	36	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	5.3	6.5	- C/ VV	

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- e. Maximum under Steady State conditions is 80 °C/W.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					L	L	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 25			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		12		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			3			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 0.5		- 1.5	V	
Oata Oarma Laskana	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 20	μΑ	
Gate-Source Leakage		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$			± 0.5		
Zara Cata Valtaga Brain Current	ı	V _{DS} = - 20 V, V _{GS} = 0 V			- 1		
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	- 19			Α	
		V _{GS} = - 10 V, I _D = - 2.2 A		0.028	0.035	1	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 1.6 A		0.036	0.043	Ω	
		V _{GS} = - 2.5 V, I _D = - 1.5 A		0.050	0.065	1	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 1.6 A		35		S	
Dynamic ^b				<u> </u>			
ut Capacitance C _{iss}				1650			
Output Capacitance		C _{oss} V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		826		pF	
Reverse Transfer Capacitance	C _{rss}			201		•	
Total Gate Charge		V _{DS} = - 10 V, V _{GS} = - 8 V, I _D = - 5 A		48	72		
	Q_g	V _{DS} = - 10 V, V _{GS} = - 4.5 V, I _D = - 5 A		19	28	nC	
Gate-Source Charge	Q _{gs}			3.3			
Gate-Drain Charge	Q _{gd}			8.4			
Gate Resistance	R _g	f = 1 MHz	0.2	1	2	kΩ	
Turn-On Delay Time	t _{d(on)}			0.71	1.1		
Rise Time	t _r	V_{DD} = - 10 V, R_L = 1 Ω		1.7	2.6		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 4.5 V, R_g = 1		6	9		
Fall Time	t _f	Ω		3.2	5		
Turn-On Delay Time	t _{d(on)}			0.3	0.45	us	
Rise Time	t _r	V_{DD} = - 10 V, R_L = 1 Ω		0.6	0.9		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 10 V, R_g = 1		10	15	1	
Fall Time	t _f	Ω	Ω 3.5		5.5	1	
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 8	A	
Pulse Diode Forward Current	I _{SM}				- 26		
Body Diode Voltage	V_{SD}	I _S = - 5 A, V _{GS} = 0 V		- 0.85	- 1.2	V	
Body Diode Reverse Recovery Time				30	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 6 A, dI/dt = 100 A/μs, T _J = 25 °C		20	40	nC	
Reverse Recovery Fall Time	ta	$i_F = 0$ A, $\alpha i / \alpha i = 100$ A/ μ s, $i_J = 25$		13		200	
Reverse Recovery Rise Time	t _b			17		ns	

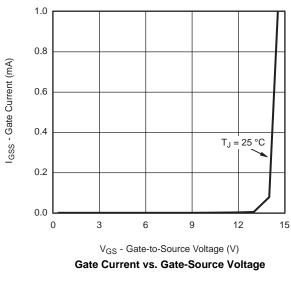
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

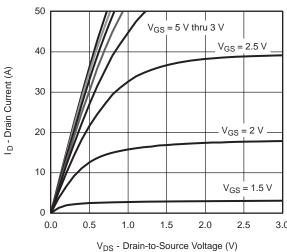
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



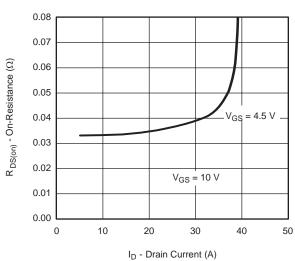
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



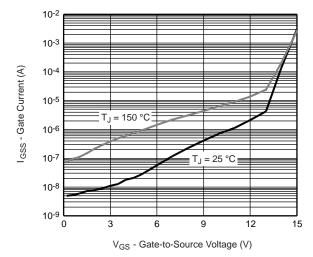
Din-Tek SEMICONDUCTOR



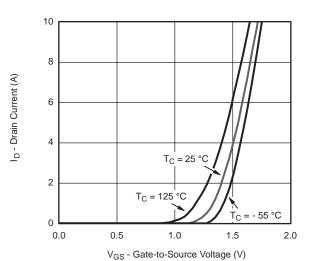
Output Characteristics



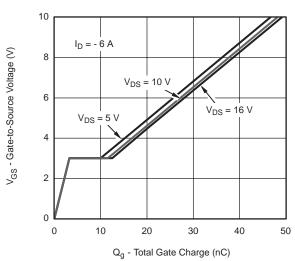
On-Resistance vs. Drain Current



Gate Current vs. Gate-Source Voltage



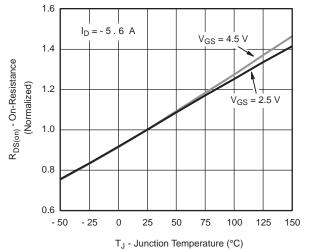
Transfer Characteristics



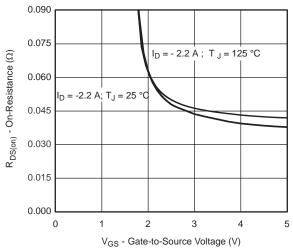
Gate Charge



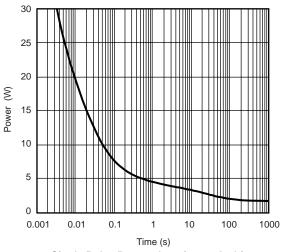
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



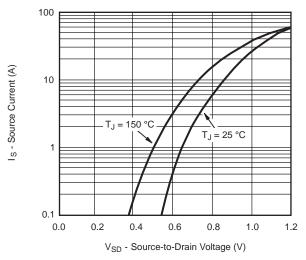
On-Resistance vs. Junction Temperature



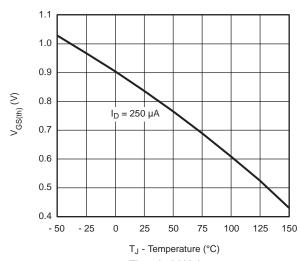
On-Resistance vs. Gate-to-Source Voltage



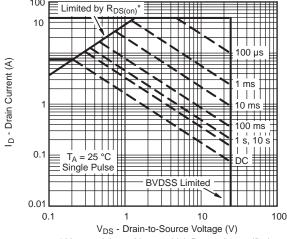
Single Pulse Power, Junction-to-Ambient



Soure-Drain Diode Forward Voltage



Threshold Voltage



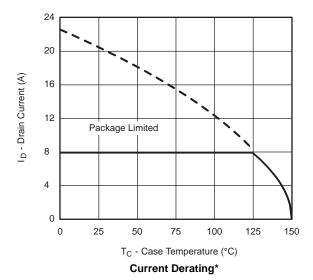
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

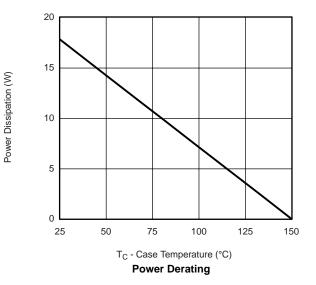
Safe Operating Area, Junction-to-Ambient



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



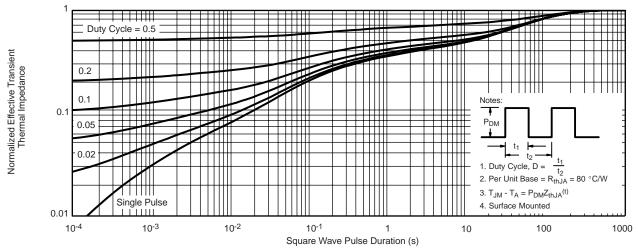


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

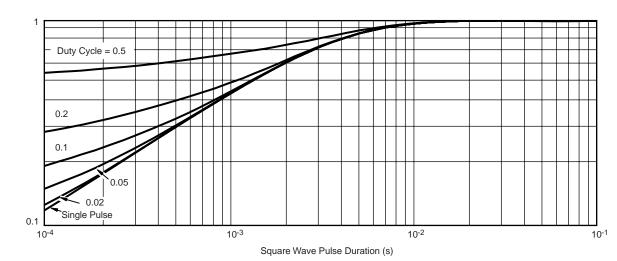


Normalized Effective Transient Thermal Impedance

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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